Oscilloscope With Debug and Analysis Capabilities

Tektronix announced a new oscilloscope that provides engineers designing high-speed digital systems with advanced debug and analysis capabilities. The TDS6604 digital storage oscilloscope is Tektronix' second generation, high-performance Silicon Germanium (SiGe) instrument. The TDS6604 gives customers the necessary performance to confront a higher level of signal integrity issues in next-gen digital design and a suite of tools to accelerate their product's development.
Featuring a sample rate of 20 gigasamples per second (GS/s) on two channels simultaneously, Tektronix's new oscilloscope offers the latest evolution in enabling design engineers to rapidly and effectively pinpoint faults in emerging high-speed serial bus architectures such as InfiniBand, RapidIO, 3GIO, and HyperTransport.
The TDS6604 digital storage oscilloscope (DSO) is a four0channel, real-time instrument that offers a 6 GHz bandwidth as well as simultaneous 20 GS/s sample rate on 2 channels. It supports single shot acquisition at 6 GHz. This performance is key to high-speed signal integrity measurement work; it enables accurate capture of the brief transients and fast signal edges that affect digital system performance.
The oscilloscope incorporates the Open Windows&reg platform providing easy access to industry standard peripherals, networking elements, and analysis tools.
The TDS6604 supports Tektronix' broad selection of automated measurement packages such as TDSJIT2 for jitter measurements, TDSUSB2 for USB 2.0 compliance testing, and more. Mask testing capabilities are available through option SM, which provides a portfolio of masks, allowing users to select from among electrical standards such as SDH/SONET, Fiber Channel, Ethernet, InfiniBand, USB, Serial ATA, and IEEE 1394, to perform compliance testing.

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